

Welcome to Galaxy Examinator reports

Date: Tue Sep 3 11:37:54 2024

Product : LotID :

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Tests Statistics

Histogram of Tests

Pareto lists: Tests Cp , Tests Cpk , Failures , Failure Signatures , Software Bin , Hardware Bin

Wafermaps & Strip Maps
Bins (Software, Hardware)
Message Log: Empty

Global information and options



Tests Statistics

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Ср	Cpk	Yield
<u>1</u>	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	30	0	0.1453	0.00215198	n/a .	n/a .	100.00 %
<u>2</u>	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	30	0	3.28267	0.00248213	n/a .	n/a .	100.00 %
<u>4</u>	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	30	0	233.333 ns	1.91785 ns	17.38	14.48	100.00 %
<u>5</u>	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	30	0	244.8 ns	1.34933 ns	24.70	23.42	100.00 %
<u>6</u>	Functional_T6 A8 0	P	1 ns	100 ns	Samples	30	0	11.4667 ns	2.22421 ns	7.42	1.57	100.00 %
<u>7</u>	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	30	0	3.28323 V	0.00173571 V	n/a .	n/a .	100.00 %
<u>8</u>	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	30	0	0.138933	0.00222731	n/a .	n/a .	100.00 %
<u>12</u>	Functional_T8 A8 0	P	1 ns	20 ns	Samples	30	9	302.933 ns	911.086 ns	0.0035	-0.1035	70.00 %
<u>786000</u>	Soft_Bin parameter	_	n/a .	n/a .	Samples	30	0	1	0	n/a .	n/a .	100.00 %
<u>786001</u>	Hard_Bin parameter	_	n/a .	n/a .	Samples	30	0	1	0	n/a .	n/a .	100.00 %
<u>786002</u>	Die_X parameter	_	n/a .	n/a .	Samples	30	0	2	1.43839	n/a .	n/a .	100.00 %
<u>786003</u>	Die_Y parameter	_	n/a .	n/a .	Samples	30	0	2.5	1.73702	n/a .	n/a .	100.00 %
<u>786004</u>	Test_Time parameter	_	0.0 sec	n/a .	Samples	30	0	2.03003 sec	0.0797057 sec	n/a .	8.49	100.00 %
<u>786006</u>	Testing_Site parameter	_	n/a .	n/a .	Samples	30	0	0	0	n/a .	n/a .	100.00 %
<u>786007</u>	Part_ID parameter	_	n/a .	n/a .	Samples	30	0	15.5	8.80341	n/a .	n/a .	100.00 %

Tests Statistics 2/25



Test

Name Functional_T5 p50 19.e128

Test type Parametric Low limit n/a . High limit n/a .

Exec / Fails 30 / 0 (0.00%)

Mean 0.1453

Sigma 0.00215198

Range 0.007

Cp / Cpk n/a . / n/a .

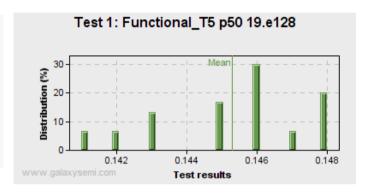
Samples 3

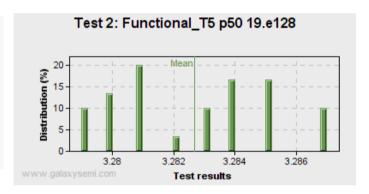


Name Functional_T5 p50 19.e128

Test type Parametric
Low limit n/a .
High limit n/a .

Exec / Fails 30 / 0 (0.00%)
Mean 3.28267
Sigma 0.00248213
Range 0.0079999
Cp / Cpk n/a . / n/a .
Samples 30





Histogram of Tests 3/25

Test 4

Name Functional_T6 p50 19.e128

 Test type
 Parametric

 Low limit
 150 ns

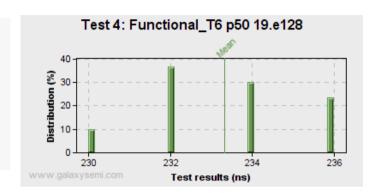
 High limit
 350 ns

 Exec / Fails
 30 / 0 (0.00%)

 Mean
 233 333 ns

Mean 233.333 ns Sigma 1.91785 ns Range 6.00001 ns Cp / Cpk 17.38 / 14.48

Samples 30

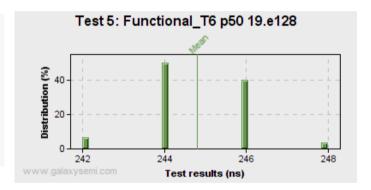




Name Functional_T6 p50 19.e128

Test type Parametric Low limit 150 ns High limit 350 ns Exec / Fails 30 / 0 (0.00%) Mean 244.8 ns Sigma 1.34933 ns 5.99999 ns Range Cp / Cpk 24.70 / 23.42

Samples 30

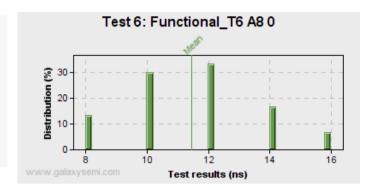


Histogram of Tests 4/25

Test <u>6</u>

Name Functional_T6 A8 0

Test type Parametric Low limit 1 ns High limit 100 ns Exec / Fails 30 / 0 (0.00%) Mean 11.4667 ns Sigma 2.22421 ns Range 8 ns Cp / Cpk 7.42 / 1.57



Test

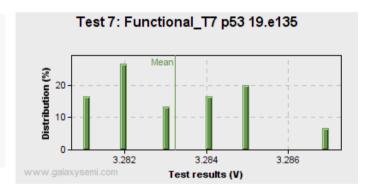
Samples

Name Functional_T7 p53 19.e135

30

Test type Parametric
Low limit n/a .
High limit n/a .

Exec / Fails 30 / 0 (0.00%)
Mean 3.28323 V
Sigma 0.00173571 V
Range 0.00600004 V
Cp / Cpk n/a . / n/a .
Samples 30



Histogram of Tests 5/25

Test 8

Name Functional_T7 p53 19.e135

 $\begin{tabular}{lll} Test type & Parametric \\ Low limit & n/a \ . \\ High limit & n/a \ . \\ \end{tabular}$

Exec / Fails 30 / 0 (0.00%)
Mean 0.138933
Sigma 0.00222731
Range 0.009
Cp / Cpk n/a . / n/a .

Samples 30



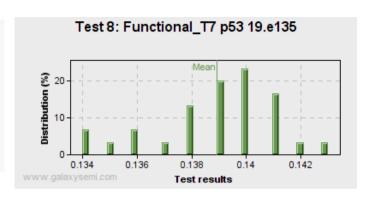
Name Functional_T8 A8 0

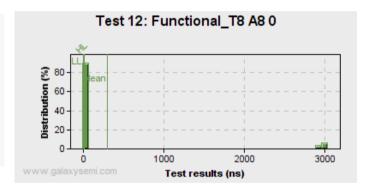
Test type Parametric
Low limit 1 ns
High limit 20 ns

Exec / Fails 30 / 9 (30.00%)
Mean 302.933 ns
Sigma 911.086 ns
Range 3044 ns

Cp / Cpk 0.0035 / -0.1035=> Warning: Process is over the high limit

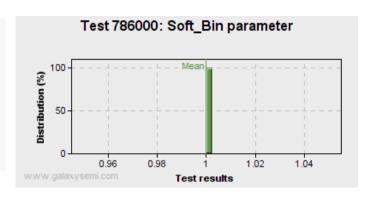
Samples 30



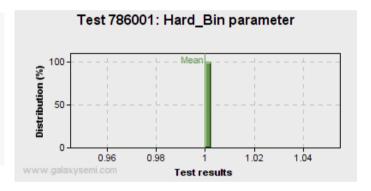


Histogram of Tests 6/25

Test 786000 Name Soft_Bin parameter Test type Low limit n/a . High limit n/a . Exec / Fails 30 / 0 (0.00%) Mean Sigma 0 Range 0 Cp / Cpk n/a . / n/a . Samples 30



Test	<u>786001</u>
Name	Hard_Bin parameter
Test type	_
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	30



Histogram of Tests 7/25

Test <u>786002</u>

Name Die_X parameter

Test type – Low limit n/a. High limit n/a.

Exec / Fails 30 / 0 (0.00%)

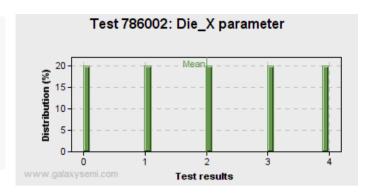
Mean

 Sigma
 1.43839

 Range
 4

 Cp / Cpk
 n/a . / n/a .

Samples 30





Test type – Low limit n/a . High limit n/a .

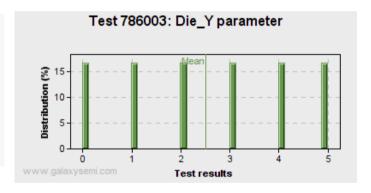
Exec / Fails 30 / 0 (0.00%)

 Mean
 2.5

 Sigma
 1.73702

 Range
 5

Samples



Histogram of Tests 8/25

Test 786004

Name Test_Time parameter

Test type

0.0 sec

Low limit High limit

n/a .

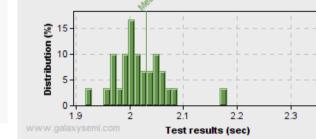
Exec / Fails Mean

30 / 0 (0.00%) 2.03003 sec

Sigma 0.0797057 sec Range 0.457 sec

Cp / Cpk n/a . / 8.49

Samples 30



Test 786004: Test_Time parameter

Test 786006 Testing_Site parameter Name Test type

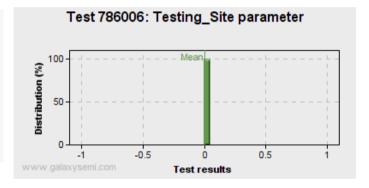
Low limit n/a . High limit n/a .

Exec / Fails 30 / 0 (0.00%)

Mean Sigma 0 Range 0

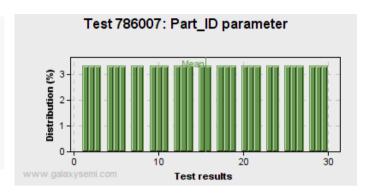
Cp / Cpk n/a . / n/a . 30

Samples



Histogram of Tests 9/25

Test	<u>786007</u>
Name	Part_ID parameter
Test type	-
Low limit	n/a .
High limit	n/a .
Exec / Fails	30 / 0 (0.00%)
Mean	15.5
Sigma	8.80341
Range	29
Cp / Cpk	n/a . / n/a .
Samples	30





Test	Name	Cp	Test Cp Chart
<u>12</u>	Functional_T8 A8 0	0.0035	

Shows all Cp <= 1.7 (Defined in Options), section 'Pareto/Define Cp cut-off limit')

Pareto of Tests Cp



Test	Name	Cpk	Test Cpk Chart
<u>12</u>	Functional_T8 A8 0	-0.1035	

Shows all Cpk <= 1.3 (Defined in Options, section 'Pareto/Define Cp cut-off limit')

Pareto of Tests Cpk 11/25



Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
<u>12</u>	Functional_T8 A8 0	-	9	30.0 %	n/a	30.0 %	
_	Cumul. of failures	-	9	30.0 %	0.0 %	30.0 %	

- -- Yield loss: number of failed test executions / number of parts
- -- Fail contribution: number of failed test executions / number of parts failed
- -- Test Fail rate: number of failed test executions / number of test executions

Pareto of Tests failures 12/25



Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **30**Total patterns detected: **1**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)
9	100.00 %	30.00 %	Functional_T8 A8 0 (Test 12)
9	100 %	-	- Total failures detected

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut-off limit')



Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected



Pareto of Software Bins 14/25



Pareto of Hardware Bins 15/25



Show Software bins

Devices tested (with retests)

Total physical parts tested 30 (only applies to Wafermaps)



Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	30

List of Individual Maps 16/25 Map style STRIP map (parts tested are PACKAGED DEVICES!) Total physical 30

parts tested

Parts processed All Data / parts (any Bin)

Data from Sites All sites

Strip started Tue Sep 03 23:24:56 2024 Strip ended Tue Sep 03 23:33:32 2024 Wafer tested in 8 minutes 36 seconds

Average device

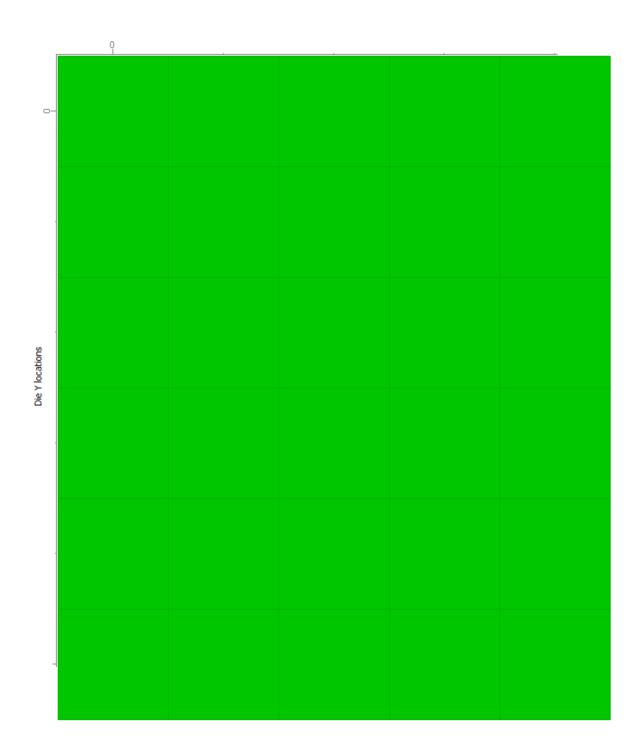
test time

17.200 sec.

Map dimensions LowX=0, LowY=0, HighX=4, HighY=5

List of Individual Maps 17/25

List of Individual Maps 18/25





List of Individual Maps 20/25



<u>Software</u> <u>Binning</u>	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	-	P	30	100.0 %	
All PASS Bin	All PASS Bins	P	30	100.0 %	
ALL Bins	ALL Bins	-	30	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Software Binning Summary 21/25



Hardware Binning Summary

<u>Hardware</u> <u>Binning</u>	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	_	P	30	100.0 %	
All PASS Bins	All PASS Bins	P	30	100.0 %	
ALL Bins	ALL Bins	_	30	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)



No log message to report



Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Tue Sep 03 11:37:54 2024
Data processed	44.6 KB (45653 bytes)
Processing time	0.37 second
Processing speed	120.8 KB/sec
Examinator expires	Sun Sep 3 2034
(null)	-
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/rahmana_i8243_p1.igxl_09032024_233054.std
Tests mapping file	n/a

Global Information 22/25

Start time Tue Sep 03 23:24:56 20:24 End time Tue Sep 03 23:33:32 20:24 Test duration 8 minutes 36 seconds Product n/a Program rahmana_i8243_p1.igxl Revision n/a Sub_Lot n/a WaferID n/a Parts processed All Data / parts (any Bin) Data from Sites All sites Test time (GODD parts) 2.030 sec. (excludes tester idle time) Test time (ALL parts) 2.030 sec. (excludes tester idle time) Average test time 17.200 sec. / device (includes tester idle time between parts) Total parts tested 30 - Includes parts retested (if any) Bad parts (Yield loss) 0 (0.00%) = Includes parts retested (if any) Bad parts (Yield loss) 0 (0.00%) Parts aborted 0 (0.00%) Includes parts retested (if any) Parts aborted 0 (0.00%) Includes parts retested (if any) Parts protested n/a Parts protested n/a Operator part Tester type Ultraft_Explus	Setup time	Tue Sep 03 23:24:56 2024
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Per_freq n/a Spec_name n/a Spec_version n/a	Aux_file	n/a
Spec_name n/a Spec_version n/a	Package type	n/a
Spec_version n/a	Per_freq	n/a
	Spec_name	n/a
Family ID n/a	Spec_version	n/a
	Family ID	n/a

Global Information 23/25

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	-
Site details	Site# 0

Global Information 24/25



Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift

Global Options 25/25